Phase Transformations: Growth Phenomena

3.205 L8 11/21/06

Today's topics:

- Diffusion-controlled vs. interface-controlled growth
- Diffusion-controlled growth: The Stefan Problem

melting of a pure material interdiffusion with a moving boundary alloy solidification

Diffusion vs. interface control

In precipitation from supersaturated solution, precipitate growth requires long-range transport of solute to the growing particle and often particle growth kinetics can be modeled by solving a diffusion problem. The growth is said to be diffusion controlled.

This is a type of moving-boundary problem; diffusional growth is often parabolic in time.

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See Figure 20.6 in Balluffi, Robert W., Samuel M. Allen, and W. Craig Carter. *Kinetics of Materials*. Hoboken, NJ: J. Wiley & Sons, 2005. ISBN: 0471246891.

Diffusion vs. interface control, cont'd

In processes like grain growth that do not involve a composition change but only interface motion, the boundary migration kinetics involve local atomic rearrangements as atoms jump from one grain to its neighbor. Such a process is said to be interface controlled.

Often, interface-controlled motion occurs at constant velocity and it is found to be linear in time.

Melting of a pure material

Melting is controlled by the rate of heat flow. We consider the motion of a planar solid/liquid interface via heat conduction:

Want to model

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•Equation of motion of solid/liquid interface

Melting of a pure material, cont'd

The description:

$$\frac{\partial T^{L}}{\partial t} = \kappa^{L} \frac{\partial^{2} T^{L}}{\partial x^{2}}$$

$$\frac{\partial T^{S}}{\partial t} = \kappa^{S} \frac{\partial^{2} T^{S}}{\partial x^{2}}$$

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$$T^{L}(x=0,t) = T^{L0} \qquad T^{L}[X(t),t] = T_{m}$$
$$T^{S}(x=\infty,t) = T^{S\infty} \qquad T^{S}[X(t),t] = T_{m}$$

Equilibrium at S/L interface

Melting of a pure material, cont'd

Heat balance at S/L interface: difference in heat fluxes must be balanced by release of latent heat associated with melting.



$$\begin{pmatrix} J^{L} - J^{S} \end{pmatrix}_{x=X} \delta t = -K^{L} \left(\frac{\partial T^{L}}{\partial x} \right)_{x=X} \delta t + K^{S} \left(\frac{\partial T^{S}}{\partial x} \right)_{x=X} \delta t = \rho H_{m} \delta X$$

$$\frac{dX}{dt} \rho H_{m} = -K^{L} \left(\frac{\partial T^{L}}{\partial x} \right)_{x=X} + K^{S} \left(\frac{\partial T^{S}}{\partial x} \right)_{x=X} \bullet \mathbf{Stefan}$$
condition

Melting of a pure material, cont'd

The solution gives a parabolic growth law

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See Figure 20.1 in Balluffi, Robert W., Samuel M. Allen, and W. Craig Carter. *Kinetics of Materials*. Hoboken, NJ: J. Wiley & Sons, 2005. ISBN: 0471246891.

$$X(t) = A\sqrt{t}$$

where

$$A = \frac{c_P^L \sqrt{4\kappa^L} (T^{L0} - T_m) \exp[-A^2/4\kappa^L]}{\sqrt{\pi}\rho H_m \operatorname{erf} \left(\frac{A}{\sqrt{4\kappa^L}}\right)}$$
$$- \frac{c_P^S \sqrt{4\kappa^S} (T_m - T^{S\infty}) \exp[-A^2/4\kappa^S]}{\sqrt{\pi}\rho H_m \operatorname{erfc} \left(\frac{A}{\sqrt{4\kappa^S}}\right)}$$

T profiles in S and L are error functions... (see *KoM* Eqs. 20.8– 20.9).

Planar growth controlled by diffusion

The solution method is analogous to that for heat-conduction controlled growth...

 $X = A\sqrt{t}$

And the growth constant, *A*, is a function of the various c's, etc. Figure removed due to copyright restrictions.

See Figure 20.2 in Balluffi, Robert W., Samuel M. Allen, and W. Craig Carter. *Kinetics of Materials*. Hoboken, NJ: J. Wiley & Sons, 2005. ISBN: 0471246891.

Solidification of a binary alloy in 1-D

A liquid alloy of concentration c_0 will reject solute ahead of the advancing S/L interface (note solute-rich boundary layer in liquid).

Figure removed due to copyright restrictions. See Figure 20.4 in Balluffi, Robert W., Samuel M. Allen, and W. Craig Carter. *Kinetics of Materials*. Hoboken, NJ: J. Wiley & Sons, 2005. ISBN: 0471246891.

Modeling requires descriptions of both temperature and concentration fields...